

JC13 Rec'd PCT/PTO 03 APR 2002

Patent

Attorney's Docket No. 033235-002**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of	)	
	)	
Toshiharu MITANI et al.	)	Group Art Unit: Unassigned
	)	
Application No.: New U.S. National Phase	)	Examiner: Unassigned
Application of PCT/JP01/06724	)	
filed August 6, 2001	)	
	)	
Filed: April 3, 2002	)	
	)	
For: METHOD FOR CONTROLLING	)	
PRODUCTION PROCESS	)	

**REQUEST FOR APPROVAL OF DRAWING CHANGES**

Assistant Commissioner for Patents  
Washington, D.C. 20231

Sir:

The Examiner's approval is respectfully requested for the proposed changes to Fig. No. 2 shown in red ink on the accompanying copy.

Upon receipt of the Examiner's approval and a Notice of Allowance, these changes will be implemented through newly submitted drawings.

Respectfully submitted,

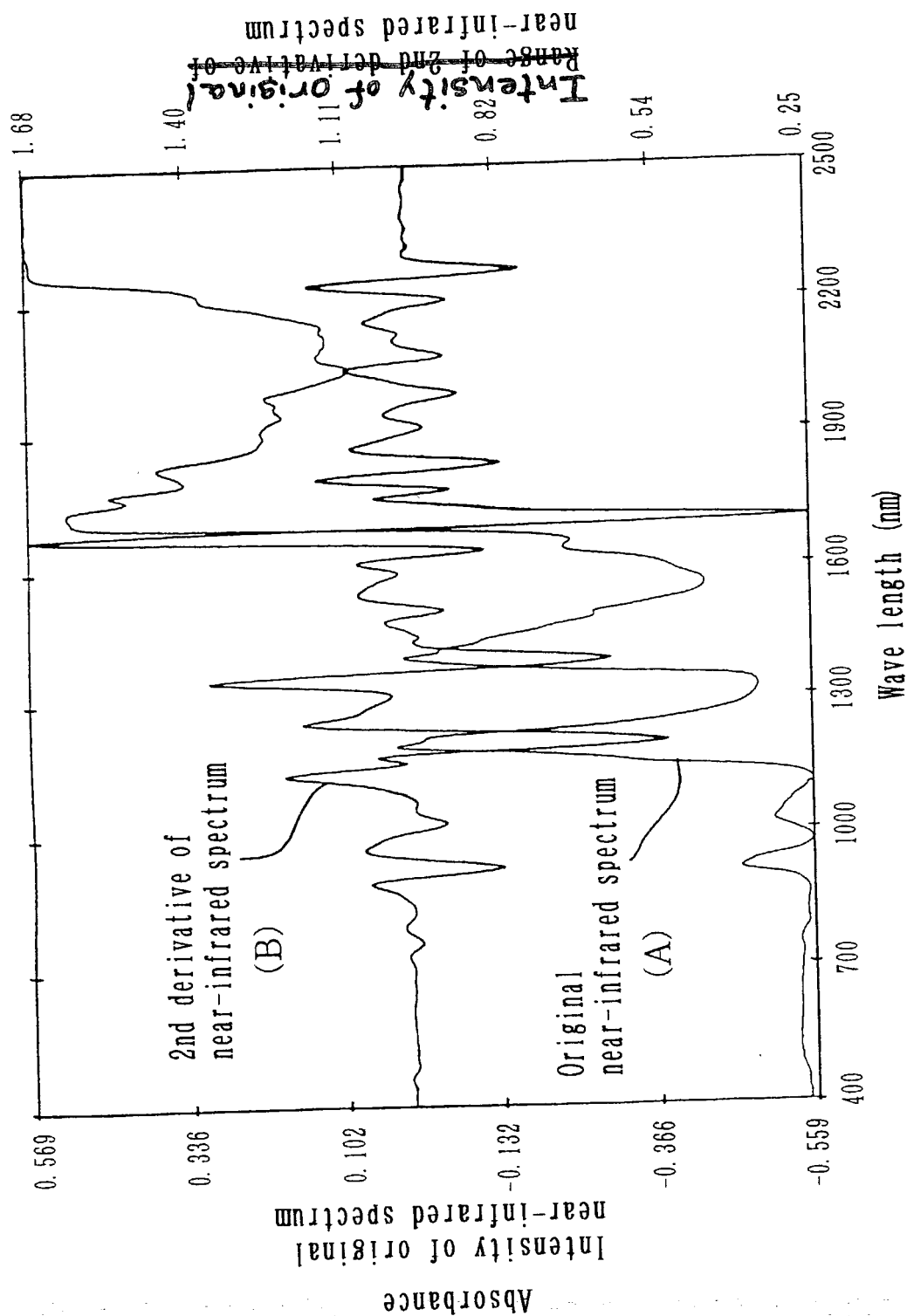
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Date: April 3, 2002

Fig. 2



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PRODUCTION PROCESS	)	

**PRELIMINARY AMENDMENT**

Assistant Commissioner for Patents  
Washington, D.C. 20231

Sir:

Prior to the first Official Action, please amend the above-identified patent application as follows:

**IN THE SPECIFICATION:**

Please replace the paragraph beginning at page 6, line 13, with the following:

(4) The method as defined in any one of the above (1) to (3), wherein the said analysis range is from 400 nm to 2,500 nm.

Please replace the paragraph beginning at page 6, line 16, with the following:

(5) The method as defined in the above (4), wherein the said analysis is from 800 nm to 2,500 nm.

**IN THE CLAIMS:**

Kindly amend claims 3, 4, 5, 6, 8, 10, and 11, and add new claims 12-20 as follows:

3. (Amended) The method as claimed in claim 2, wherein the deviations (analysis deviations) of the analysis intensities from the standard average intensity are discriminated as to whether or not they are within the tolerance limit determined based on the standard deviations given in the data base for the standard samples.

4. (Amended) The method as claimed in claim 3, wherein the said analysis range is from 400 nm to 2,500 nm.

5. (Amended) The method as claimed in claim 4, wherein the said analysis range is from 800 nm to 2,500 nm.

6. (Amended) The method as claimed in claim 5, wherein the selected wave lengths stand each other at a distance of 10 nm or less.

8. (Amended) The method as claimed in claim 7, wherein the absorbance spectrum is processed by differentiation.

10. (Amended) The method as claimed in claim 9, wherein the data base is constructed from a plurality of standard samples of a plurality of kinds, by calculating the standard average intensity and standard deviations for each kind.

11. (Amended) The method as claimed in claim 10, wherein absorbance spectra are obtained for a plurality of the analysis samples and estimating the deviations of average intensities of the analysis samples (analysis average intensity) at the selected wave lengths from the standard average intensity.

12. (New) The method as claimed in claim 1, wherein the deviations (analysis deviations) of the analysis intensities from the standard average intensity are discriminated as to whether or not they are within the tolerance limit determined based on the standard deviations given in the data base for the standard samples.

13. (New) The method as claimed in claim 1, wherein the said analysis range is from 400 nm to 2,500 nm.

14. (New) The method as claimed in claim 13, wherein the said analysis range is from 800 nm to 2,500 nm.

15. (New) The method as claimed in claim 1, wherein the selected wave lengths stand each other at a distance of 10 nm or less.

16. (New) The method as claimed in claim 15, wherein the selected wave lengths stand each other at a distance of 2 nm or less.

17. (New) The method as claimed in claim 1, wherein the absorbance spectrum is processed by differentiation.

18. (New) The method as claimed in claim 17, wherein the absorbance spectrum is processed by building up the second derivative thereof.

19. (New) The method as claimed in claim 1, wherein the data base is constructed from a plurality of standard samples of a plurality of kinds, by calculating the standard average intensity and standard deviations for each kind.

20. (New) The method as claimed in claim 1, wherein absorbance spectra are obtained for a plurality of the analysis samples and estimating the deviations of average intensities of the analysis samples (analysis average intensity) at the selected wave lengths from the standard average intensity.

Application No. Unassigned  
Attorney's Docket No. 033235-002  
Page 5

**REMARKS**


By the present Preliminary Amendment, claims 4 and 5 have been amended so that the proper relationship in ranges is provided and a corresponding revision has been made in the specification. In addition, all multiple dependency has been eliminated from the original claims (with a typographical error further being corrected in claim 3) and new claims 12-20 have been added to encompass certain aspects of the invention within the scope of the original multiple dependent claims. It is to be understood that the revisions to the claims are solely for formalistic purposes and not with regard to patentability and that applicants reserve the right to pursue claims directed to other aspects of the invention encompassed by the original multiple dependent claims or described in the specification.

Entry of the instant Preliminary Amendment and favorable consideration on the merits are respectfully requested.

Should the Examiner have any questions concerning the subject application, the Examiner is invited to contact the undersigned attorney at the number provided below.

Respectfully submitted,

BURNS, DOANE, SWECKER & MATHIS, L.L.P.

By:   
Robert G. Mukai  
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(703) 836-6620

Date: April 3, 2002

**Attachment to Preliminary Amendment dated April 3, 2002**

**Marked-up Copy of the Specification**

Paragraph beginning at page 6, line 13

(4) The method as defined in any one of the above (1) to (3), wherein the said analysis range is from [800] 400 nm to 2,500 nm.

Paragraph beginning at page 6, line 16

(5) The method as defined in the above (4), wherein the said analysis is from [400] 800 nm to 2,500 nm.



**Attachment to Preliminary Amendment dated April 3, 2002**

**Marked-up Claims 3, 4, 6, 8, 10 and 11**

3. (Amended) The method as claimed in claim [1 or] 2, wherein the deviations (analysis deviations) of the analysis intensities from the standard average intensity are discriminated as to whether or not they are within the tolerance limit determined based on the standard deviations given in the data base for the standard [stantard] samples.

4. (Amended) The method as claimed in claim [any one of claims 1 to] 3, wherein the said analysis range is from [800] 400 nm to 2,500 nm.

5. (Amended) The method as claimed in claim 4, wherein the said analysis range is from [400] 800 nm to 2,500 nm.

6. (Amended) The method as claimed in claim [any one of claims 1 to] 5, wherein the selected wave lengths stand each other at a distance of 10 nm or less.

8. (Amended) The method as claimed in claim [any one of claims 1 to] 7, wherein the absorbance spectrum is processed by differentiation.

10. (Amended) The method as claimed in claim [any one of claims 1 to] 9, wherein the data base is constructed from a plurality of standard samples of a plurality of kinds, by calculating the standard average intensity and standard deviations for each kind.

11. (Amended) The method as claimed in claim [any one of claims 1 to] 10, wherein absorbance spectra are obtained for a plurality of the analysis samples and estimating the deviations of average intensities of the analysis samples (analysis average intensity) at the selected wave lengths from the standard average intensity.